

High Speed CMOS Logic Hex Inverting Schmitt Trigger

Features

- Unlimited Input Rise and Fall Times
- Exceptionally High Noise Immunity
- Fanout (Over Temperature Range)
 - Standard Outputs 10 LSTTL Loads
 - Bus Driver Outputs 15 LSTTL Loads
- Wide Operating Temperature Range . . . -55°C to 125°C
- Balanced Propagation Delay and Transition Times
- Significant Power Reduction Compared to LSTTL Logic ICs
- HC Types
 - 2V to 6V Operation
 - High Noise Immunity: $N_{IL} = 30\%$, $N_{IH} = 30\%$ of V_{CC} at $V_{CC} = 5V$
- HCT Types
 - 4.5V to 5.5V Operation
 - Direct LSTTL Input Logic Compatibility, $V_{IL} = 0.8V$ (Max), $V_{IH} = 2V$ (Min)
 - CMOS Input Compatibility, $I_I \leq 1\mu A$ at V_{OL} , V_{OH}

Description

The 'HC14 and 'HCT14 each contain 6 inverting Schmitt Triggers in one package.

Ordering Information

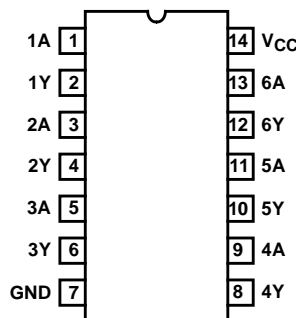
PART NUMBER	TEMP. RANGE (°C)	PACKAGE
CD54HC14F	-55 to 125	14 Ld CERDIP
CD54HC14F3A	-55 to 125	14 Ld CERDIP
CD74HC14E	-55 to 125	14 Ld PDIP
CD74HC14M	-55 to 125	14 Ld SOIC
CD54HCT14F	-55 to 125	14 Ld CERDIP
CD54HCT14F3A	-55 to 125	14 Ld CERDIP
CD74HCT14E	-55 to 125	14 Ld PDIP
CD74HCT14M	-55 to 125	14 Ld SOIC

NOTES:

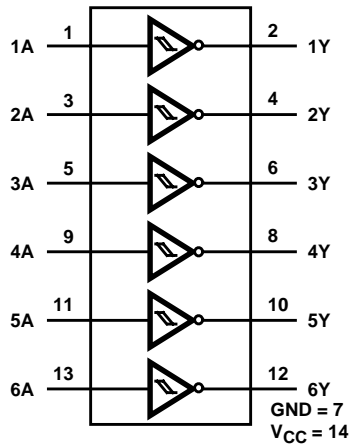
1. When ordering, use the entire part number. Add the suffix 96 to obtain the variant in the tape and reel.
2. Die is available which meets all electrical specifications. Please contact your local TI sales office or customer service for ordering information.

Pinout

CD54HC14, CD54HCT14
(CERDIP)
CD74HC14, CD74HCT14
(PDIP, SOIC)
TOP VIEW



Functional Diagram



TRUTH TABLE

INPUT (A)	OUTPUT (Y)
L	H
H	L

NOTE:
 H= High Level
 L = Low Level

Logic Diagram



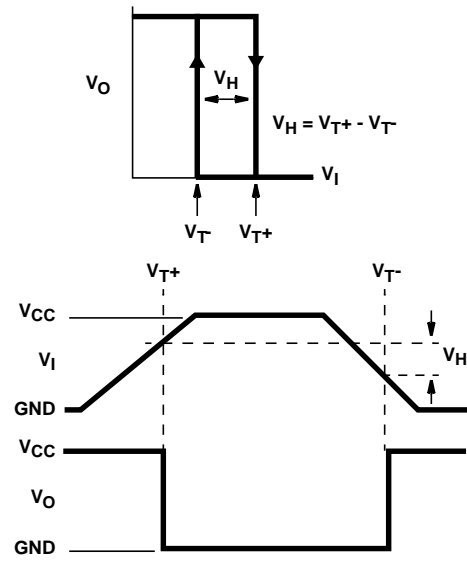


FIGURE 1. HYSTERESIS DEFINITION, CHARACTERISTIC, AND TEST SETUP

CD54/74HC14, CD54/74HCT14

Absolute Maximum Ratings

DC Supply Voltage, V_{CC}	-0.5V to 7V
DC Input Diode Current, I_{IK}	
For $V_I < -0.5V$ or $V_I > V_{CC} + 0.5V$	$\pm 20mA$
DC Output Diode Current, I_{OK}	
For $V_O < -0.5V$ or $V_O > V_{CC} + 0.5V$	$\pm 20mA$
DC Drain Current, per Output, I_O	
For $-0.5V < V_O < V_{CC} + 0.5V$	$\pm 25mA$
DC Output Source or Sink Current per Output Pin, I_O	
For $V_O > -0.5V$ or $V_O < V_{CC} + 0.5V$	$\pm 25mA$
DC V_{CC} or Ground Current, I_{CC}	$\pm 50mA$

Thermal Information

Thermal Resistance (Typical, Note 3)	θ_{JA} ($^{\circ}C/W$)	θ_{JC} ($^{\circ}C/W$)
PDIP Package	90	-
CERDIP Package	130	55
SOIC Package	120	-
Maximum Junction Temperature (Hermetic Package or Die) . . .	175 $^{\circ}C$	
Maximum Junction Temperature (Plastic Package)	150 $^{\circ}C$	
Maximum Storage Temperature Range	-65 $^{\circ}C$ to 150 $^{\circ}C$	
Maximum Lead Temperature (Soldering 10s)	300 $^{\circ}C$	
	(SOIC - Lead Tips Only)	

Operating Conditions

Temperature Range, T_A	-55 $^{\circ}C$ to 125 $^{\circ}C$
Supply Voltage Range, V_{CC}	
HC Types2V to 6V
HCT Types4.5V to 5.5V
DC Input or Output Voltage, V_I, V_O	0V to V_{CC}
Input Rise and Fall Time, t_r, t_f	
2V	100ms (Max)
4.5V	100ms (Max)
6V	100ms (Max)

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

NOTE:

- θ_{JA} is measured with the component mounted on an evaluation PC board in free air.

DC Electrical Specifications

PARAMETER	SYMBOL	TEST CONDITIONS		V_{CC} (V)	25 $^{\circ}C$		-40 $^{\circ}C$ TO 85 $^{\circ}C$		-55 $^{\circ}C$ TO 125 $^{\circ}C$		UNITS
		V_I (V)	I_O (mA)		MIN	MAX	MIN	MAX	MIN	MAX	
HC TYPES											
Input Switch Points	V_{T+}	-	-	2	0.7	1.5	0.7	1.5	0.7	1.5	V
				4.5	1.7	3.15	1.7	3.15	1.7	3.15	V
				6	2.1	4.2	2.1	4.2	2.1	4.2	V
	V_{T-}	-	-	2	0.3	1.0	0.3	1.0	0.3	1.0	V
				4.5	0.9	2.2	0.9	2.2	0.9	2.2	V
				6	1.2	3.0	1.2	3.0	1.2	3.0	V
	V_H	-	-	2	0.2	1.0	0.2	1.0	0.2	1.0	V
				4.5	0.4	1.4	0.4	1.4	0.4	1.4	V
				6	0.6	1.6	0.6	1.6	0.6	1.6	V
High Level Output Voltage CMOS Loads	V_{OH}	V_{T-} or V_{T+}	-0.02	2	1.9	-	1.9	-	1.9	-	V
			-0.02	4.5	4.4	-	4.4	-	4.4	-	V
			-0.02	6	5.9	-	5.9	-	5.9	-	V
High Level Output Voltage TTL Loads		-	-	-	-	-	-	-	-	-	V
		-4	4.5	3.98	-	3.84	-	3.7	-	-	V
		-5.2	6	5.48	-	5.34	-	5.2	-	-	V

CD54/74HC14, CD54/74HCT14

DC Electrical Specifications (Continued)

PARAMETER	SYMBOL	TEST CONDITIONS		V_{CC} (V)	25°C		-40°C TO 85°C		-55°C TO 125°C		UNITS
		V_I (V)	I_O (mA)		MIN	MAX	MIN	MAX	MIN	MAX	
Low Level Output Voltage CMOS Loads	V_{OL}	V_{IH} or V_{IL}	0.02	2	-	0.1	-	0.1	-	0.1	V
			0.02	4.5	-	0.1	-	0.1	-	0.1	V
			0.02	6	-	0.1	-	0.1	-	0.1	V
Low Level Output Voltage TTL Loads	V_{OL}	V_{IH} or V_{IL}	-	-	-	-	-	-	-	-	V
			4	4.5	-	0.26	-	0.33	-	0.4	V
			5.2	6	-	0.26	-	0.33	-	0.4	V
Input Leakage Current	I_I	V_{CC} or GND	-	6	-	± 0.1	-	± 1	-	± 1	μA
Quiescent Device Current	I_{CC}	V_{CC} or GND	0	6	-	2	-	20	-	40	μA
HCT TYPES											
Input Switch Points	V_{T+}	-	-	4.5	1.2	1.9	1.2	1.9	1.2	1.9	V
				5.5	1.4	2.1	1.4	2.1	1.4	2.1	V
	V_{T-}			4.5	0.5	1.2	0.5	1.2	0.5	1.2	V
				5.5	0.6	1.4	0.6	1.4	0.6	1.4	V
				V_H	4.5	0.4	1.4	0.4	1.4	0.4	1.4
5.5	0.4	1.5	0.4		1.5	0.4	1.5	V			
High Level Output Voltage CMOS Loads	V_{OH}	V_{IH} or V_{IL}	-0.02	4.5	4.4	-	4.4	-	4.4	-	V
High Level Output Voltage TTL Loads			-4	4.5	3.98	-	3.84	-	3.7	-	V
Low Level Output Voltage CMOS Loads	V_{OL}	V_{IH} or V_{IL}	0.02	4.5	-	0.1	-	0.1	-	0.1	V
Low Level Output Voltage TTL Loads			4	4.5	-	0.26	-	0.33	-	0.4	V
Input Leakage Current	I_I	V_{CC} and GND	-	5.5	-	± 0.1	-	± 1	-	± 1	μA
Quiescent Device Current	I_{CC}	V_{CC} or GND	0	5.5	-	2	-	20	-	40	μA
Additional Quiescent Device Current Per Input Pin: 1 Unit Load	ΔI_{CC} (Note 4)	V_{CC} - 2.1	-	4.5 to 5.5	-	360	-	450	-	490	μA

NOTE:

4. For dual-supply systems theoretical worst case ($V_I = 2.4V$, $V_{CC} = 5.5V$) specification is 1.8mA.

HCT Input Loading Table

INPUT	UNIT LOADS
nA	0.6

NOTE: Unit Load is ΔI_{CC} limit specified in DC Electrical Specifications table, e.g., 360 μA max at 25°C.

CD54/74HC14, CD54/74HCT14

Switching Specifications Input $t_r, t_f = 6\text{ns}$

PARAMETER	SYMBOL	TEST CONDITIONS	V_{CC} (V)	25°C			-40°C TO 85°C		-55°C TO 125°C		UNITS
				MIN	TYP	MAX	MIN	MAX	MIN	MAX	
HC TYPES											
Propagation Delay, A to Y	t_{PLH}, t_{PHL}	$C_L = 50\text{pF}$	2	-	-	135	-	170	-	205	ns
		$C_L = 50\text{pF}$	4.5	-	-	27	-	34	-	41	ns
		$C_L = 15\text{pF}$	5	-	11	-	-	-	-	-	ns
		$C_L = 50\text{pF}$	6	-	-	23	-	29	-	35	ns
Output Transition Times	t_{TLH}, t_{THL}	$C_L = 50\text{pF}$	2	-	-	75	-	95	18	110	ns
			4.5	-	-	15	-	19	-	22	ns
			6	-	-	13	-	16	-	19	ns
Input Capacitance	C_I	-	-	-	10	-	10	-	10	pF	
Power Dissipation Capacitance (Notes 5, 6)	C_{PD}	-	5	-	20	-	-	-	-	pF	
HCT TYPES											
Propagation Delay, A to Y	t_{PLH}, t_{PHL}	$C_L = 50\text{pF}$	4.5	-	-	38	-	48	-	57	ns
		$C_L = 15\text{pF}$	5	-	16	-	-	-	-	-	ns
Output Transition Times	t_{TLH}, t_{THL}	$C_L = 50\text{pF}$	4.5	-	-	15	-	19	-	22	ns
Input Capacitance	C_I	-	-	-	10	-	10	-	10	pF	
Power Dissipation Capacitance (Notes 5, 6)	C_{PD}	-	5	-	20	-	-	-	-	pF	

NOTES:

5. C_{PD} is used to determine the dynamic power consumption, per inverter.
6. $P_D = V_{CC}^2 f_i (C_{PD} + C_L)$ where f_i = input frequency, C_L = output load capacitance, V_{CC} = supply voltage.

Test Circuits and Waveforms

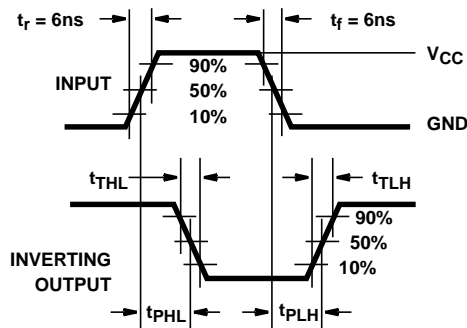


FIGURE 2. HC TRANSITION TIMES AND PROPAGATION DELAY TIMES, COMBINATION LOGIC

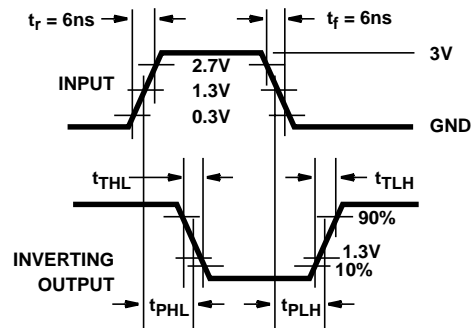


FIGURE 3. HCT TRANSITION TIMES AND PROPAGATION DELAY TIMES, COMBINATION LOGIC

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